

Institutional Sign In

Browse

My Settings

Get Help

Subscribe

Show with

Show All Results

Per Page: Per Page 25

Export

Alert Set Search Alerts

Search History

Sort By: Sort Relevance

Displaying results 1-25 of 32 for (((brewing) AND chamber) AND valve) x

☐ Journals & Magazines (20)

☐ Conferences (9)

☐ Books (3)

Filter results by

Search within results

Content Type ^

☐ Journals & Magazines (20)

☐ Conferences (9)

☐ Books (3)

Year ^

Single Year

Range

☐

1904

From

1904

To

2017

☐

Author v

Affiliation v

Publication Title v

Publisher v

Conference Location v

Evolution of generation in parallel with the network

P. W. Evans | D. W. Hadfield | R. Kasher
IEE Colloquium on Parallel Operation of Generating Plant within a Public
Electricity Supply Network
Year: 1991

☐ Evolution of generation in parallel with the network

P. W. Evans; D. W. Hadfield; R. Kasher

IEE Colloquium on Parallel Operation of Generating Plant within a Public

Electricity Supply Network

Year: 1991

Pages: 3/1 - 312

IET Conferences

Abstract

(420 Kb)

High-end server low-temperature cooling

R. R. Schmidt | B. D. Notohardjono
IBM Journal of Research and Development
Year: 2002 | Volume: 46 | Issue: 6

☐ High-end server low-temperature cooling

R. R. Schmidt; B. D. Notohardjono

IBM Journal of Research and Development

Year: 2002, Volume: 46, Issue: 6

Pages: 739 - 751

Cited by: Papers (16) | Patents (9)

IBM Journals & Magazines

Abstract

(438 Kb)

Thermal and electrical barrier performance testing of ultrathin atomic layer deposition tantalum-based materials for nanoscale copper metallization

O. van der Straten | Y. Zhu | E. Eisenbraun | A. Kaloyeros
Proceedings of the IEEE 2002 International Interconnect Technology
Conference (Cat. No.02EX519)
Year: 2002

☐ Thermal and electrical barrier performance testing of ultrathin atomic layer deposition tantalum-based materials for nanoscale copper metallization

O. van der Straten; Y. Zhu; E. Eisenbraun; A. Kaloyeros

Proceedings of the IEEE 2002 International Interconnect Technology

Conference (Cat. No.02EX519)

Year: 2002

Pages: 188 - 190

Cited by: Patents (30)

IEEE Conferences

Abstract

(287 Kb)

Quantitative Neurophysiology

Joseph V. Tranquillo

Year: 2008

☐ **Quantitative Neurophysiology**

Joseph V. Tranquillo

Year: 2008

Morgan and Claypool eBooks

Abstract

Comparative study of the vibrating armature and rotary vane pumps

Adrian Turcanu

2017 International Conference on Electromechanical and Power Systems (SIELMEN)

Year: 2017

☐ **Comparative study of the vibrating armature and rotary vane pumps**

Adrian Turcanu

2017 International Conference on Electromechanical and Power Systems (SIELMEN)

Year: 2017

Pages: 094 - 099

IEEE Conferences

Abstract

(592 Kb)

Classification of instant coffee odors by electronic nose toward quality control of production

Treenet Thepudom | Nuttawoot Sricharoenchai | Teerakiat Kerdcharoen

2013 10th International Conference on Electrical Engineering/Electronics, Computer, Telecommunications and Information Technology

Year: 2013

☐ **Classification of instant coffee odors by electronic nose toward quality control of production**

Treenet Thepudom; Nuttawoot Sricharoenchai; Teerakiat Kerdcharoen

2013 10th International Conference on Electrical Engineering/Electronics, Computer, Telecommunications and Information Technology

Year: 2013

Pages: 1 - 4

Cited by: Papers (3)

IEEE Conferences

Abstract

(524 Kb)

The interactive balloon: Sensing, actuation and behavior in a common object

J. A. Paradiso

IBM Systems Journal

Year: 1996 | Volume: 35 | Issue: 3.4

☐ **The interactive balloon: Sensing, actuation and behavior in a common object**

J. A. Paradiso

IBM Systems Journal

Year: 1996, Volume: 35, Issue: 3.4

Pages: 473 - 487

Cited by: Papers (2) | Patents (4)

IBM Journals & Magazines

Abstract (6117 Kb)

Integrated processing for microelectronics science and technology

G. W. Rubloff | D. T. Bordonaro
IBM Journal of Research and Development
Year: 1992 | Volume: 36 | Issue: 2

- ☐ **Integrated processing for microelectronics science and technology**
G. W. Rubloff; D. T. Bordonaro
IBM Journal of Research and Development
Year: 1992, Volume: 36, Issue: 2
Pages: 233 - 276
Cited by: Papers (3) | Patents (2)
IBM Journals & Magazines

Abstract (3932 Kb)

Present Fellows

A Century of Honors: The First One-Hundred Years of Award Winners, Honorary Members, Past Presidents, and Fellows of the Institute
Year: 1984

- ☐ **Present Fellows**
A Century of Honors: The First One-Hundred Years of Award Winners, Honorary Members, Past Presidents, and Fellows of the Institute
Year: 1984
Wiley-IEEE Press eBook Chapters

Abstract

Nonlinear sensorless cooling control for a peltier actuated aluminum plate thermal system

Kazuki Takahashi | Mingcong Deng
Proceedings of the 2013 International Conference on Advanced Mechatronic Systems
Year: 2013

- ☐ **Nonlinear sensorless cooling control for a peltier actuated aluminum plate thermal system**
Kazuki Takahashi; Mingcong Deng
Proceedings of the 2013 International Conference on Advanced Mechatronic Systems
Year: 2013
Pages: 1 - 715
Cited by: Papers (1)
IEEE Conferences

Abstract (123309 Kb)

« First < < 1 2 > > Last »

IEEE Account	Purchase Details	Profile Information	Need Help?
» Change Username/Password	» Payment Options	» Communications Preferences	» US & Canada: +1 800 678 4333
» Update Address	» Order History	» Profession and Education	» Worldwide: +1 732 981 0060
	» View Purchased Documents	» Technical Interests	» Contact & Support

[About IEEE Xplore](#) | [Contact Us](#) | [Help](#) | [Accessibility](#) | [Terms of Use](#) | [Nondiscrimination Policy](#) | [Sitemap](#) | [Privacy & Opting Out of Cookies](#)

A not-for-profit organization, IEEE is the world's largest technical professional organization dedicated to advancing technology for the benefit of humanity.
© Copyright 2018 IEEE - All rights reserved. Use of this web site signifies your agreement to the terms and conditions.

IEEE Account

Profile Information

Purchase Details

Need Help?

Other

A not-for-profit organization, IEEE is the world's largest technical professional organization dedicated to advancing technology for the benefit of humanity.
© Copyright 2018 IEEE - All rights reserved. Use of this web site signifies your agreement to the terms and conditions.

US & Canada: +1 800 678 4333
Worldwide: +1 732 981 0060